

## PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449  O 1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT  JAN 03 2002 (Use several sheets if necessary)		ATTY. DOCKET NO. 10002450-1	APPLICATION NO. 09/727,188	CONFIRMATION NO.
		APPLICANT Clinton M. Ramsey		
		FILING DATE Nov. 30, 2000	GROUP 2125	

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
Amv	1A 5,956,476	Sep. 21, 1999	Ranson et al.	395	183.06
Amv	1B 6,018,623	Jan. 25, 2000	Chang et al.	395	500.07
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION
							YES
	1L						
	1M						
	1N						
	1O						
	1P						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

Amv	1Q	"Statistical Modeling for Efficient Parametric Yield Estimation of MOS VLSI Circuits" Paul Cox et al., IEEE Trans. Electron. Devices, Vol. ED-32 No. 2, pp. 471-478, 1985
	1R	
	1S	

EXAMINER <i>Albert W. Paladini</i>	ALBERT W. PALADINI PATENT EXAMINER	DATE CONSIDERED <i>5-28-02</i>
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